

# SLOVENSKI STANDARD oSIST prEN IEC 61554:2024

01-julij-2024

### Oprema za panelno vgradnjo - Električni merilni instrumenti - Vgradne mere

Panel mounted equipment - Electrical measuring instruments - Dimensions for panel mounting

Appareils montés en tableaux - Instruments de mesure électriques - Dimensions pour le montage en tableaux

## Ta slovenski standard je istoveten z: prEN IEC 61554:2024

o<u>SIST prEN\_IEC\_61554:2024</u> https://<u>ICS:</u>ards.iteh.ai/catalog/standards/sist/67c0e0ed-f614-4a7c-bde2-68e1cc540905/osist-pren-iec-61554-2024 17.220.20 Merjenje električnih in Measurement of electrical magnetnih veličin and magnetic quantities

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# 85/913/CDV

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Secretariat:		SECRETARY:	
China		Ms Guiju HAN	
OF INTEREST TO THE FOL	LOWING COMMITTEES:	PROPOSED HORIZONTAL STA	ANDARD:
		Other TC/SCs are requested any, in this CDV to the sec	ed to indicate their interest, if cretary.
FUNCTIONS CONCERNED:			
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CENELEC online voting		EC 61554:2024	
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#### TITLE:

Panel mounted equipment - Electrical measuring instruments - Dimensions for panel mounting

PROPOSED STABILITY DATE: 2027

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39		PANEL MOUNTED EQUI	PMENT –
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41		DIMENSIONS FOR PANEL	MOUNTING
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45		FOREWORD	
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85 86		IEC 61554 has been prepared by IEC technical committee 85: Measuring equipment for electrical and electromagnetic quantities.	
87	Th	his second edition cancels and replaces the first edition	on published in 1999.

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- This edition includes the following significant technical changes with respect to the previous edition:
- a) Complement more sizes and tolerances of instruments and some practical information for
  panel mounting which were not mentioned in IEC 61554:1999;
- b) Modify several current sizes and tolerance of instruments ;
- 93 c) Update the Figures in Annex A;
- d) Change Annex A from Informative Annex into Nornative Annex.
- <sup>95</sup> The text of this International Standard is based on the following documents:

FDIS	Report on voting
XXX	XXX

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Full information on the voting for its approval can be found in the report on voting indicated in the above table.

<sup>99</sup> The language used for the development of this International Standard is English.

100 This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in 101 accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available 102 at www.iec.ch/members\_experts/refdocs. The main document types developed by IEC are 103 described in greater detail at www.iec.ch/standardsdev/publications.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- 108 withdrawn,

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